

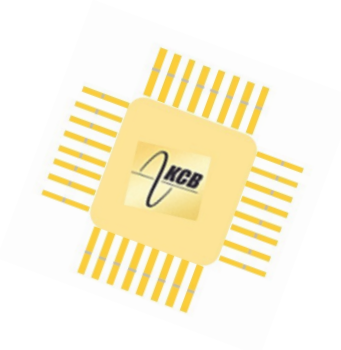
# KCB828

High Isolation SP4T  
0.02 – 4 GHz



## DESCRIPTION

KCB828 is a GaAs pHEMT Non-Reflective high performance, low loss switch in a 32 lead quad flat, Hermetic Surface-Mount Technology (SMT) package for Harsh Environments ideal for Defense and Satellite application. This device can be ordered with the 100% screening requirements of MIL-PRF-38535 Class B and S, in addition to the required QCI.



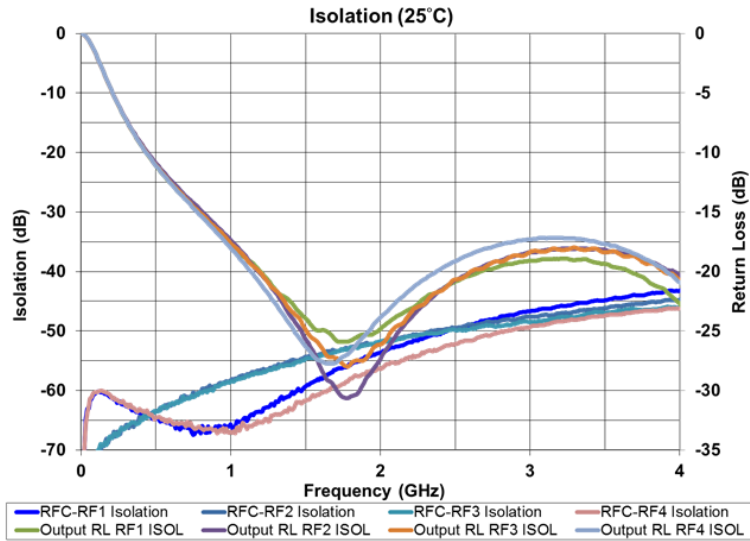
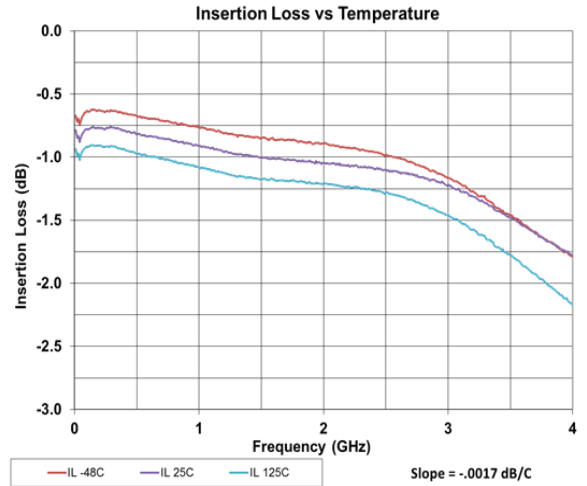
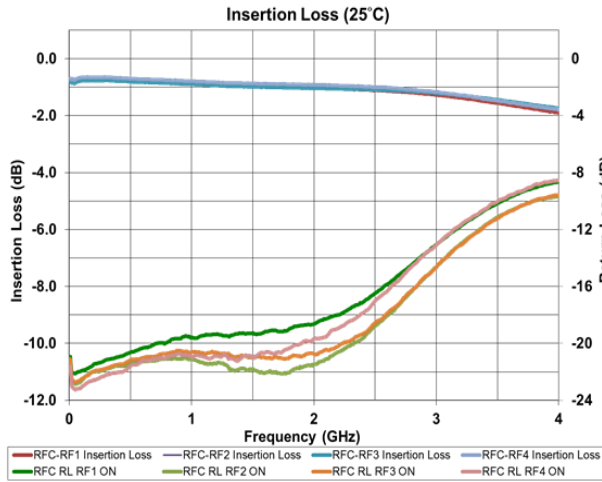
## FEATURES

- ✓ **Low Loss: 1.0 dB @ 2 GHz; Isolation: 50 dB @ 2 GHz.**
- ✓ **Non Reflective Match in Off State (S22).**
- ✓ **NASA EEE-INST-002 compliant.**
- ✓ **Successfully Tested to 1M RAD TID.**
- ✓ **High Reliability Class B and S Screening Available.**
- ✓ **See Page 5 for MFR HI –REL Ordering Details.**

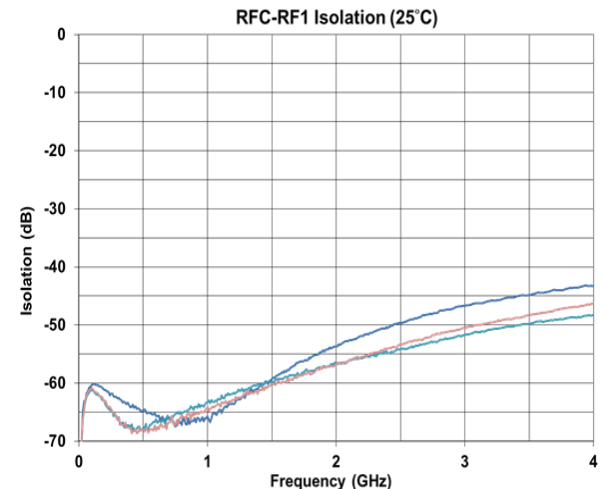
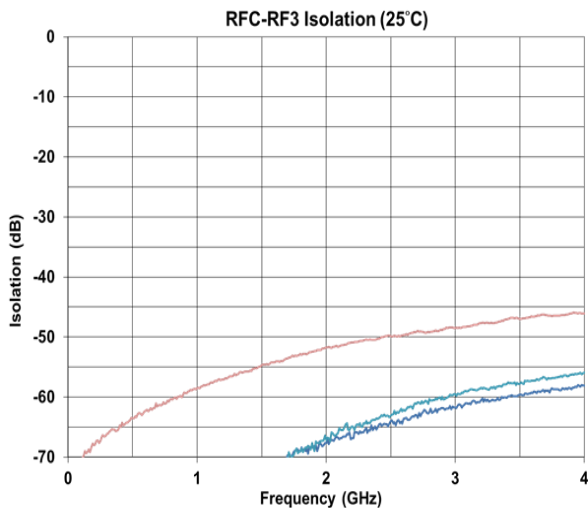
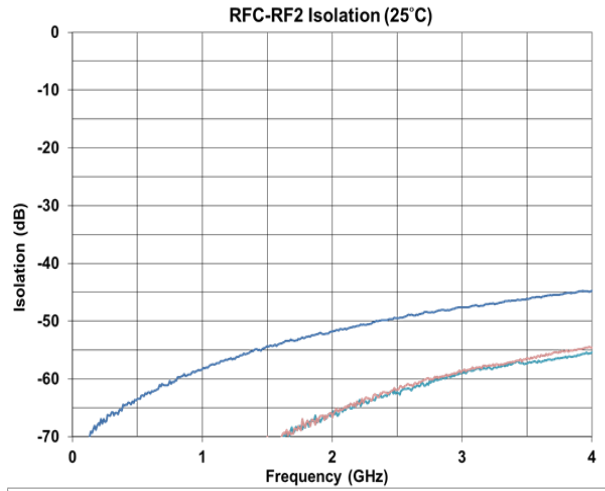
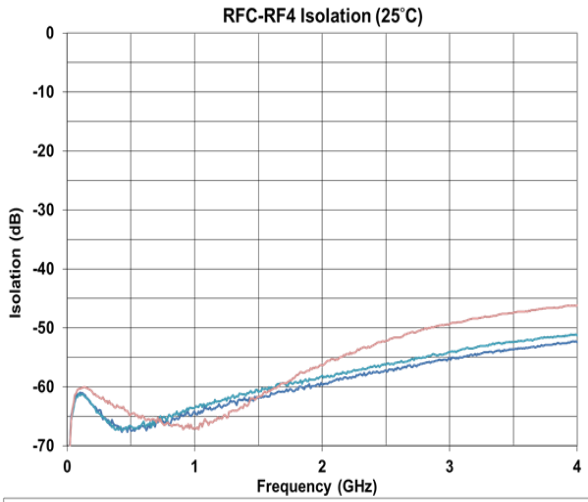
## ELECTRICAL CHARACTERISTICS (+25°C)

Parameter	Conditions	Min	Typical	Max	Units
Insertion Loss	DC – 1.0 GHz		0.9	1.10	dB
	1.0 – 2.0 GHz		1.0	1.20	dB
	2.0 – 2.5 GHz		1.1	1.30	dB
	2.5 – 4.0 GHz		1.5	1.90	dB
RF1/RF2 Return Loss (ON-State)	0.02 – 2.0 GHz	19	22		dB
	2.0 – 3.0 GHz	15	22		dB
	3.0 – 4.0 GHz	12	18		dB
RF1/RF2 Return Loss (OFF-State)	0.02 – 0.1 GHz	0	0		dB
	0.1 – 0.5 GHz	5	8		dB
	0.5 – 2.0 GHz	9	11		dB
	2.0 – 3.0 GHz	12	15		dB
	3.0 – 4.0 GHz	12	15		dB
Isolation	DC – 1.0 GHz	45	55		dB
	1.0 – 2.0 GHz	40	50		dB
	2.0 – 2.5 GHz	35	45		dB
	2.5 – 4.0 GHz	33	38		dB
1 dB Input Compression (P1dB)	Vdd = 5V		+30		dBm
Third Order Output Intercept Point (IP3)	+7 dBm Input Tones, 1 MHz Spacing		+47		dBm
Switching Speed:					
	(Rise/Fall) (ON/OFF)	10/90% or 90/10% RF 50%CTL to 90/10% RF		40 125	nS nS

TYPICAL PERFORMANCE (+25°C)



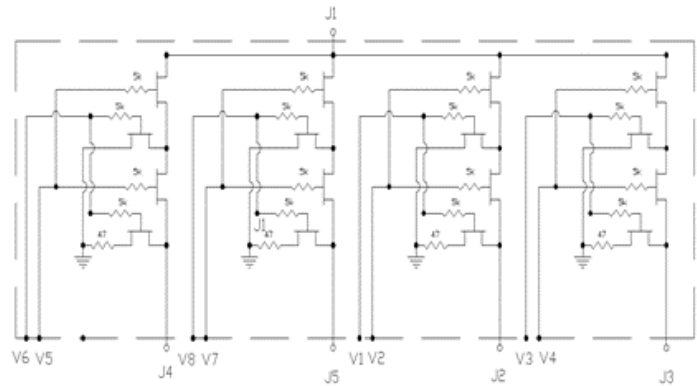
TYPICAL PERFORMANCE (+25°C)



## TRUTH TABLE/NEGATIVE CONTROL

RF Path "On"	Ctl 1	Ctl 2	Ctl 3	Ctl 4	Ctl 5	Ctl 6	Ctl 7	Ctl 8
RFC – RF1	0	-5	-5	0	-5	0	-5	0
RFC – RF2	-5	0	0	-5	-5	0	-5	0
RFC – RF3	-5	0	-5	0	0	-5	-5	0
RFC – RF4	-5	0	-5	0	-5	0	0	-5

## SCHEMATIC



## TRUTH TABLE/POSITIVE CONTROL

RF Path "On"	Ctl 1	Ctl 2	Ctl 3	Ctl 4	Ctl 5	Ctl 6	Ctl 7	Ctl 8
RFC – RF1	+5	0	0	+5	0	+5	0	+5
RFC – RF2	0	+5	+5	0	0	+5	0	+5
RFC – RF3	0	+5	0	+5	+5	0	0	+5
RFC – RF4	0	+5	0	+5	0	+5	+5	0

Note: External blocking capacitors are required on all RF ports for positive control operation. Capacitor should be selected to allow for low frequency operation.

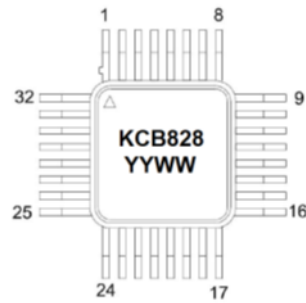
## PINOUT

1	GND	17	CTL8
2	GND	18	CTL7
3	GND	19	CTL6
4	RFC	20	CTL5
5	GND	21	CTL4
6	GND	22	CTL3
7	GND	23	CTL2
8	GND	24	CTL1
9	N/C	25	N/C
10	GND	26	GND
11	RF1	27	RF3
12	GND	28	GND
13	RF2	29	RF4
14	GND	30	GND
15	GND	31	GND
16	N/C	32	N/C

## ABSOLUTE MAXIMUM RATINGS

Exceeding Max limits may cause damage

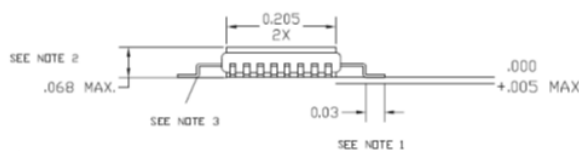
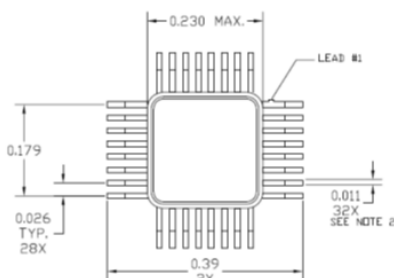
Characteristic	Min.	Max.	Units
Control Voltage Positive control (0/+5)	-0.2	+9.0	Volts
Control Voltage (A+B) Negative Control (-5/0)	-9.0	+0.2	
RF Input Power		+30	dBm
Storage Temperature	-65	+150	°C
Operating Case Temp	-55	+125	°C
Junction Temperature		+175	°C



XXX = Serial number will be added for Class B and S Part numbers

## OUTLINE DRAWING

Dimensions are shown in inches.



Electrostatic Sensitive Device. Proper ESD precaution should be used when handling device.

## MFR HI-REL SCREENING FLOW

Test Inspection	MIL – STD -883		Requirement	
	Method	Condition	Class B	Class S
Wafer Lot Acceptance /1	5007		N/A	Per Wafer Lot
Non-Destructive Bond Pull	2023		SPC	SPC
Internal Visual	2010	A= Class S, B = Class B	100%	100%
Temperature Cycle	1010	C	100%	100%
Acceleration	2001	E (Y1 only)	100%	100%
PIND	2020	A ( 5 Cycles)	N/A	100%
Serialization	Per Product Specification		100%	100%
Radiographic	2012	2 views	N/A	100%
Electrical Test	Small Signal Testing	+25°C	100%	100%
Burn In	1015	A	100%/160 Hours/125°C	100%/240 Hours/125 °C
Final Electrical	Small Signal Testing	+25°C	100%	100%
PDA Calculation	5004	25% Δ IL / 100% Δ Icc	5%	5%/3% functional
Group A Electrical /5	Per Product Specification	-55°C + 125°C	45/0	45/0
Leak Test	1014 A and C	1 x 10 -8 Max	100%	100%
External Visual	2009		100%	100%

## NOTES

- Product under configuration control per KCB QAP 015.
- Customer will be notified of all class 1 changes for Class B and S part numbers.
- Wafer Lot Acceptance will include 100% die visual, SEM analysis and Lot Traceability.
- Electrical Test Data will be recorded for each serial number and included in Final Test Report for all Class S part numbers.
- Group A Electrical testing will include the Small Signal and Ic at the Min/Max operating condition. The Dynamic test (P1dB, IP3, SS) will be tested at +25c only.

## ORDERING INFORMATION

	Unscreened	Class B	Class S
KCB Solutions Part Number	KCB828C	KCB828B	KCB828S

